Search Notes

	Application/Control No.	Applicant(s)/Patent under Reexamination
Search Notes ‖‖‖‖‖‖‖‖‖‖	10/725,378	FAN ET AL.
	Examiner	**Art Unit**	
	Peter Coughlan	2129	

SEARCHED

Class	Subclass	Date	Examiner
706	8	11/2/2007	PDC
706	16	11/2/2007	PDC
706	45	11/2/2007	PDC
706	49	11/2/2007	PDC
703	2	11/2/2007	PDC
703	9	11/2/2007	PDC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East-inductive learning, learning model, feature vector, aggregate benefit, application, purpose, function, fan wei	11/2/2007	PDC
East--II--Wang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	11/2/2007	PDC
IEEE--Wang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	11/2/2007	PDC
IEEE--II--inductive learning, learning model, feature vector, aggregae benefit, application, purpose, function, fan wei	11/2/2007	PDC
Google-inductive learning, learning model, feature vector, aggregae benefit, application, purpose, function, fan wei	11/2/2007	PDC
Dogpile--Wang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	11/2/2007	PDC
Inventors--Wang Haixun, Yu Philip S, Fan Wei	**11/2/2007**	**PDC**